

<b>Notice of References Cited</b>	Application/Control No. 10/033,031	Applicant(s)/Patent Under Reexamination INOUE, RUMIKO	
	Examiner Brian D. Nguyen	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,614,781	09-2003	Elliott et al.	370/352
*	B	US-6,965,562	11-2005	Tuomi, Jukka	370/230
*	C	US-6,600,735	07-2003	Iwama et al.	370/352
*	D	US-6,654,366	11-2003	Ketcham, Carl	370/352
*	E	US-2002/0101860	08-2002	Thornton et al.	370/352
*	F	US-2003/0179753	09-2003	Mercuriali, Jean-Pierre	370/395.2
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	2000-196664	07-2000	JP	Lucent Technologies Inc.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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